

TRACKER 2000

General purpose troubleshooting



The Huntron Tracker 2000 provides advanced troubleshooting capabilities to simplify testing newer technology components such as CMOS and MOS circuits. Its built-in pulse generator lets you thoroughly troubleshoot gate-fired devices such as SCRs, TRIACs and optocouplers. By energizing the gate, you can test a component in an active mode.

You use a Tracker 2000 while the power to the circuitry you're testing is turned off. This avoids accidental shorts that could cause further damage. It allows you to analyze the overall health of a solid-state component, which makes it perfect for finding leakage or substrate damage that has brought a system or circuit board down prematurely. Because it can compare suspect components to known good equivalents, it's also ideal for troubleshooting when documentation is missing or incomplete.

Real-world troubleshooting challenges

The Huntron Tracker 2000 is ideal for troubleshooting Programmable Logic Controls (PLCs). In troubleshooting multi-channel input modules, technicians frequently run into a damaged channel because the IC buffers, optocouplers and drivers have been over-stressed. By using the pulse generator built into the Tracker 2000, you can quickly troubleshoot optocouplers and other gate-fired devices. Simply compare signatures of one channel against another. You will usually find problems where you see differences in signatures. Likewise, you can compare multichannel outputs with the Tracker 2000. These devices usually fail when too much current is drawn through the driver section. To troubleshoot them, compare the signatures of ICs in one channel against those in another, looking for differences that indicate a problem.

Ordering Information

The Huntron Tracker 2000 comes complete with Huntron MP10 Microprobes (one pair), common test leads, two mini-clip leads, power cord and instruction manual.

- Test components and boards without power - ideal for catastrophic failures
- Get a picture of a component's overall health - including intermittent problems
- Test gate-fired devices with a built-in pulse generator
- Non-destructive testing

Ranges

Ranges	V _s (V _{pk})	Z _s (kΩ)	I _{sc} (mA _{rms})	P _{max} (mW)	P _{diode} (mW)
High	60	74	0.6	6	0.2
Medium 2	20	27	0.6	2	0.2
Medium 1	15	1.2	8.5	23	2
Low	10	54Ω	132	232	33

Specifications

Input Selection	A, B, Alternate (variable rate)
Test Frequencies	50/60Hz, 400Hz, 2000Hz
Functions	
Range Selection	Manual or AutoScan High Range Lockout
Alternation Rate	Adjustable (0.5 to 10Hz)
Pulse Generator	
Level	0V to 5V
DC Mode	+DC or -DC
Pulse Mode	+Pulse, -Pulse, or both; adjustable duty cycle
Line Voltage	100VAC, 115VAC or 230VAC
Line Frequency	47 to 400Hz
Power	20 Watts maximum
Display	2.8 in (7.0 cm) diag CRT
Dimensions	11 in L x 9 in W x 4 in H (28 cm L x 23 cm W x 10 cm H)
Weight	7lb. (3.2kg)
Operating Temp	+32°F to +122°F (0°C to +50°C)
Storage Temp	-58°F to +140°F (-50°C to +60°C)
Warranty	1 year, limited